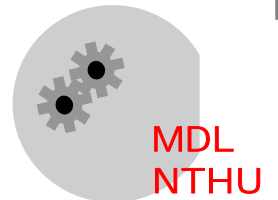


Outline

- 1 Introduction**
- 2 Basic IC fabrication processes**
- 3 Fabrication techniques for MEMS**
- 4 Applications**
- 5 Mechanics issues on MEMS**



3. Fabrication Techniques for MEMS

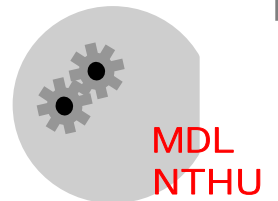
3.1 Bulk micromachining

3.2 Surface micromachining

3.3 LIGA process

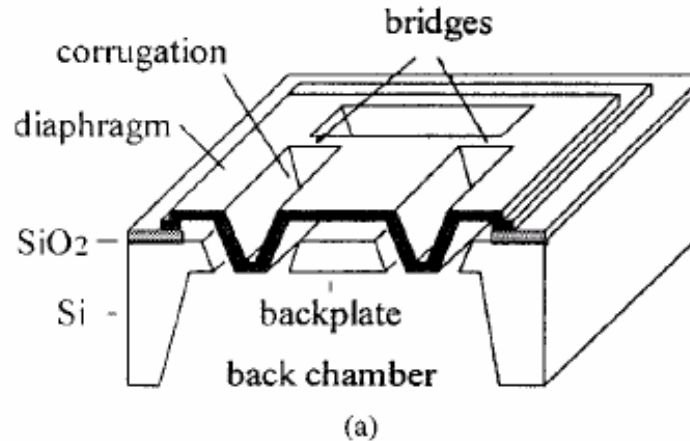
3.4 Hybrid micromachining

3.5 Thick micromachined structures



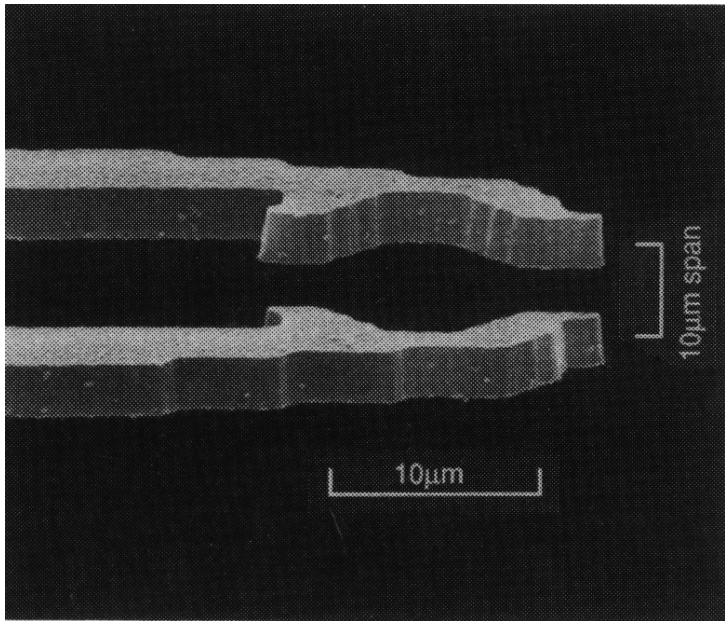
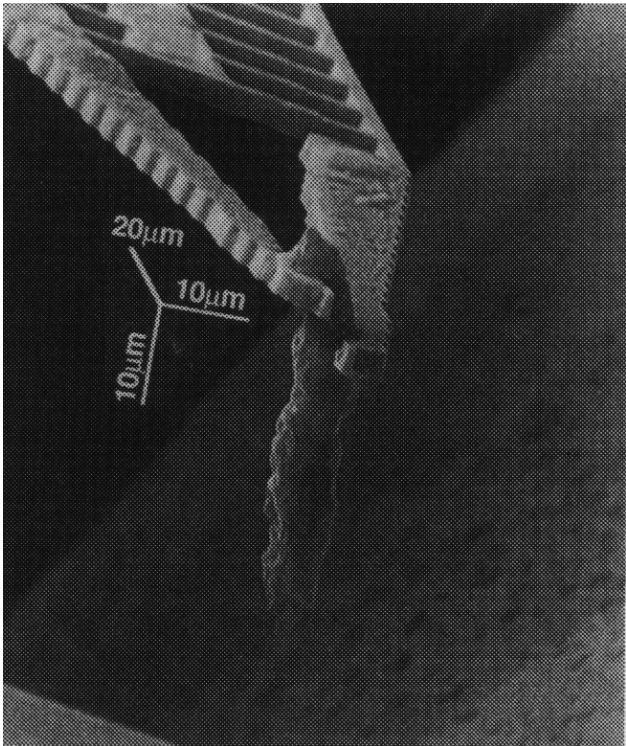
3.4 Hybrid micromachining

- Hybrid micromachining – the fabrication processes containing both surface and bulk micromachining technique
- Presently, more and more MEMS devices are fabricated through hybrid micromachining technique



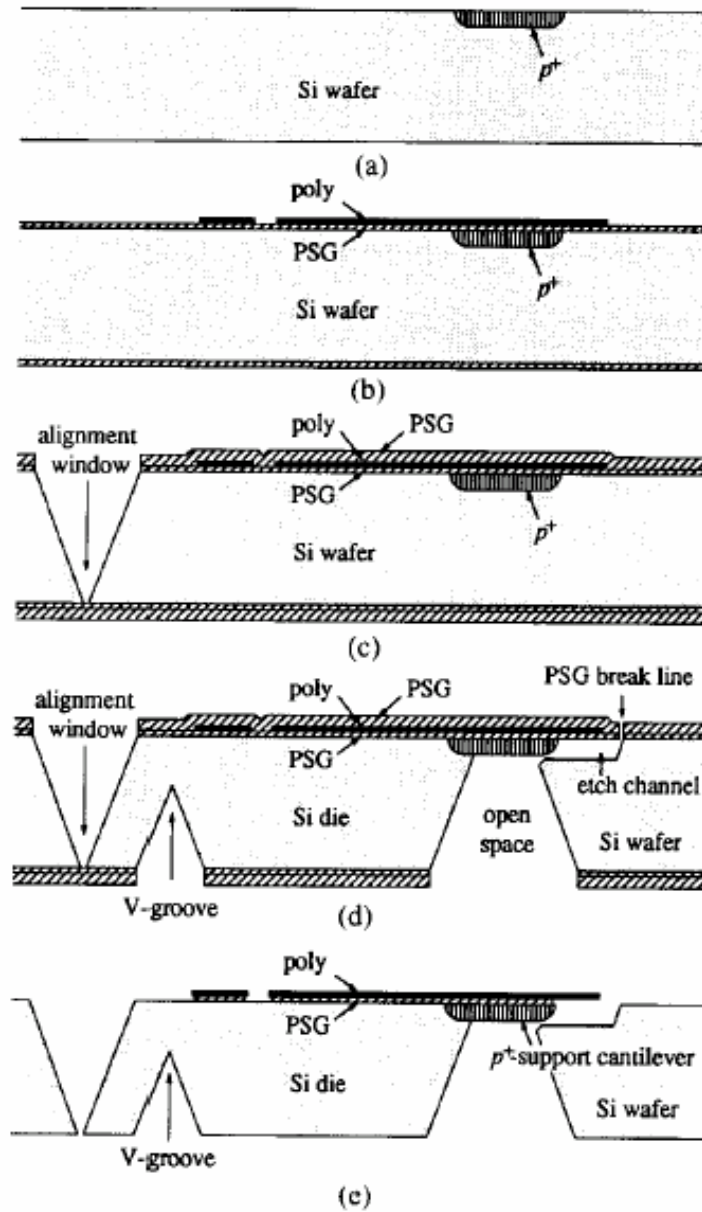
Q. Zou, Z. Li, and L. Liu, J. of MEMS, 1996

Micro Gripper

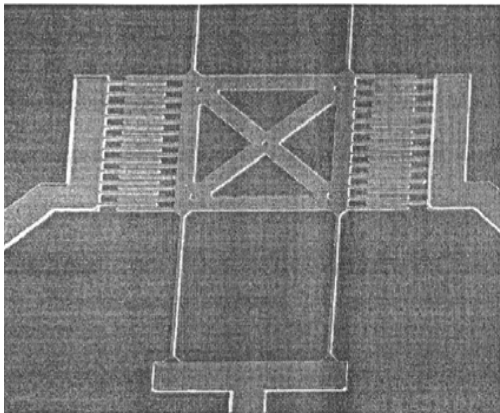
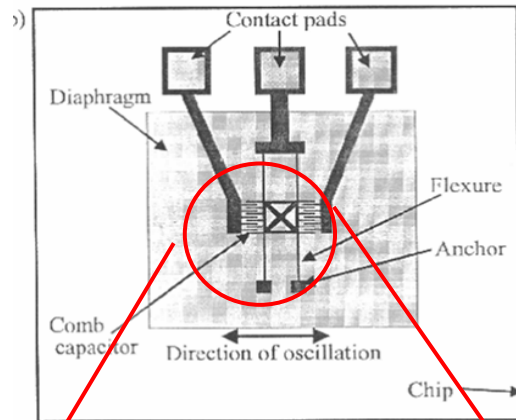


C.-J. Kim, A.P. Pisano, and R.S. Muller, J. of MEMS, 1992

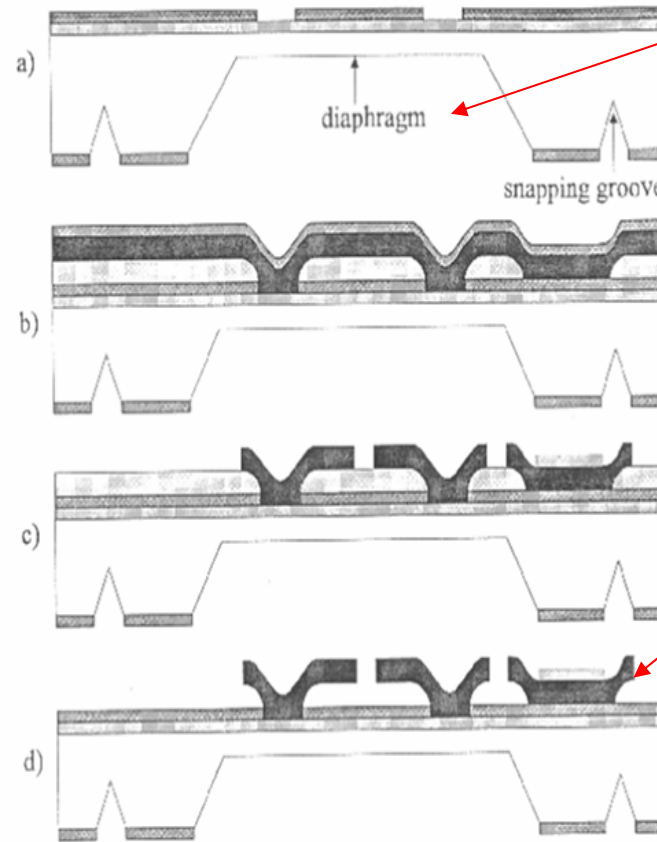
+ Fabrication processes



Resonant pressure transducer



surface micromachined resonator

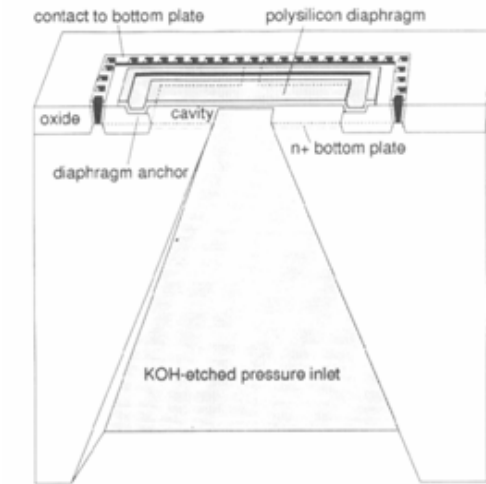
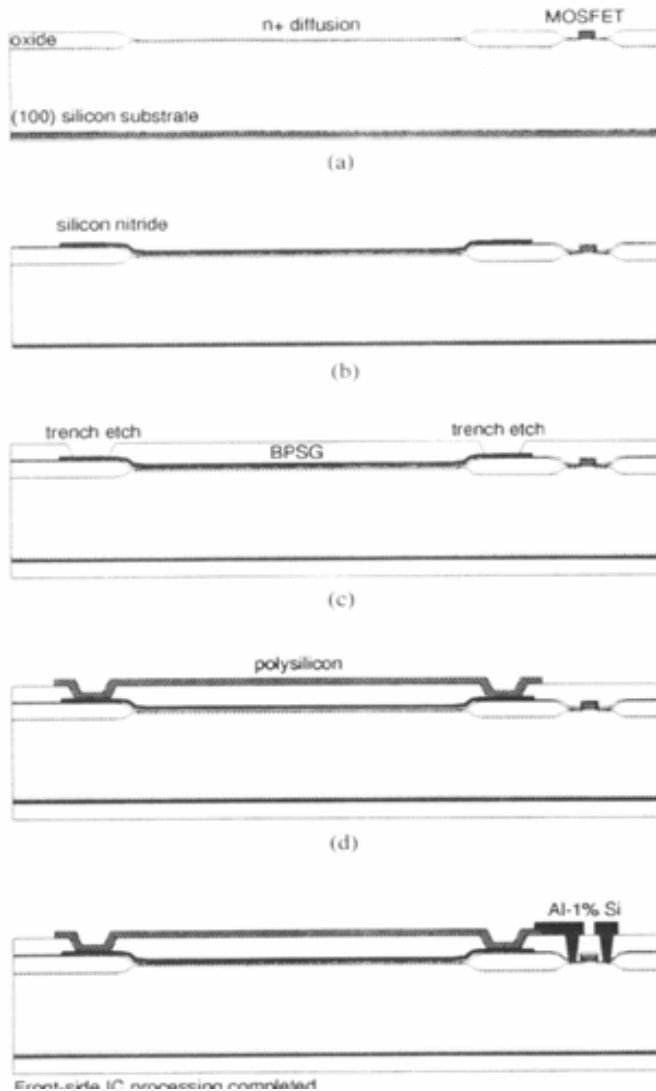


Bulk silicon etching

Surface micromachined resonator

C.J. Welham, J.W. Gardner, and J. Greenwood, *Transducer '95*, 1995.

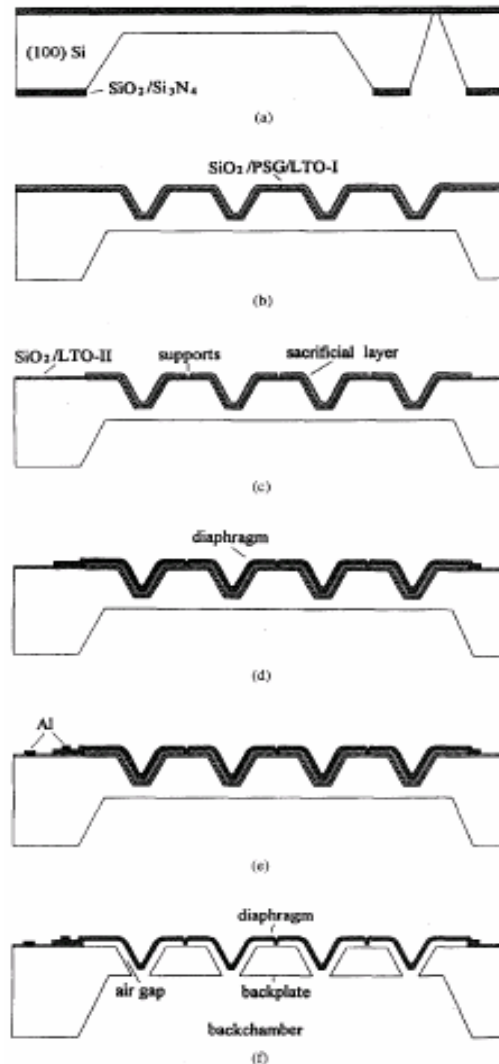
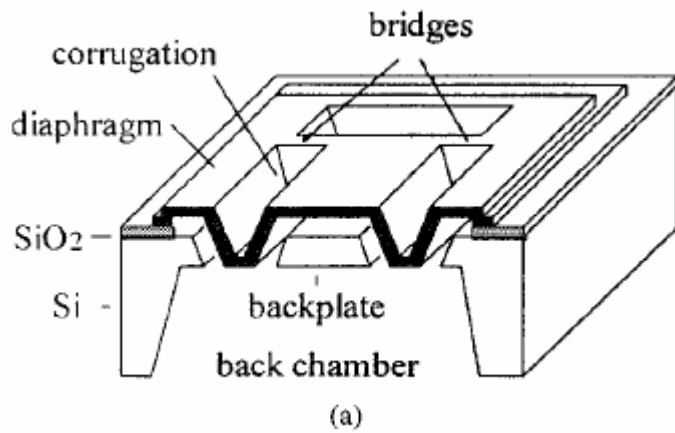
Capacitive type pressure transducer



Air-gap capacitor structure implemented using an existing

J.T. Kung and H.-S. Lee, J. of MEMS, 1992.

Microphone



Q. Zou, Z. Li, and L. Liu,
J. of MEMS, 1996

Electrostatic lever actuator



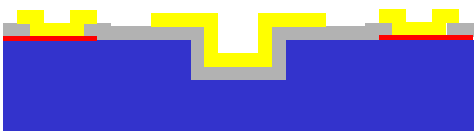
DRIE trench



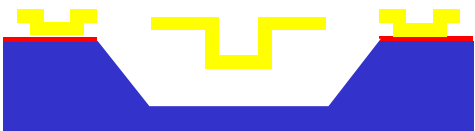
define wet anisotropic etch mask



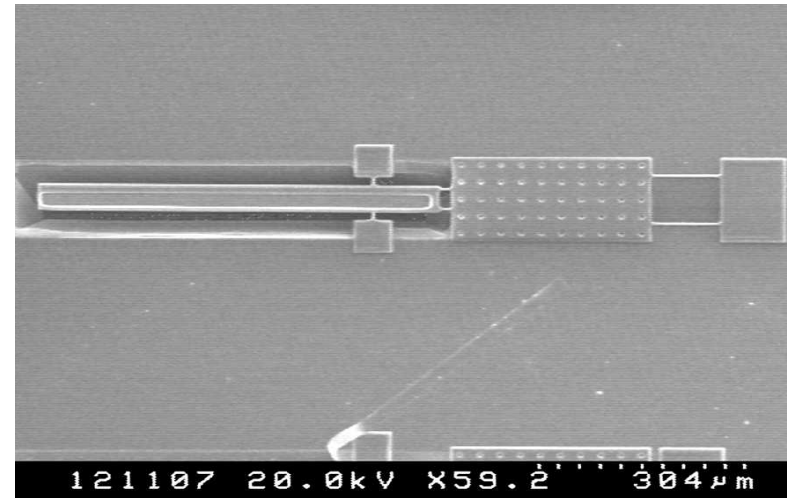
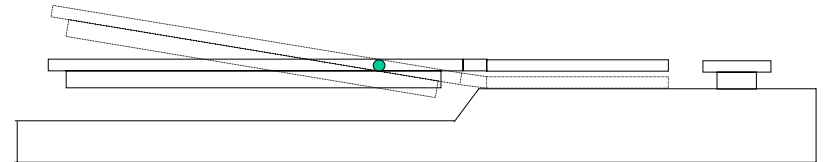
define sacrificial layer



define structure layer

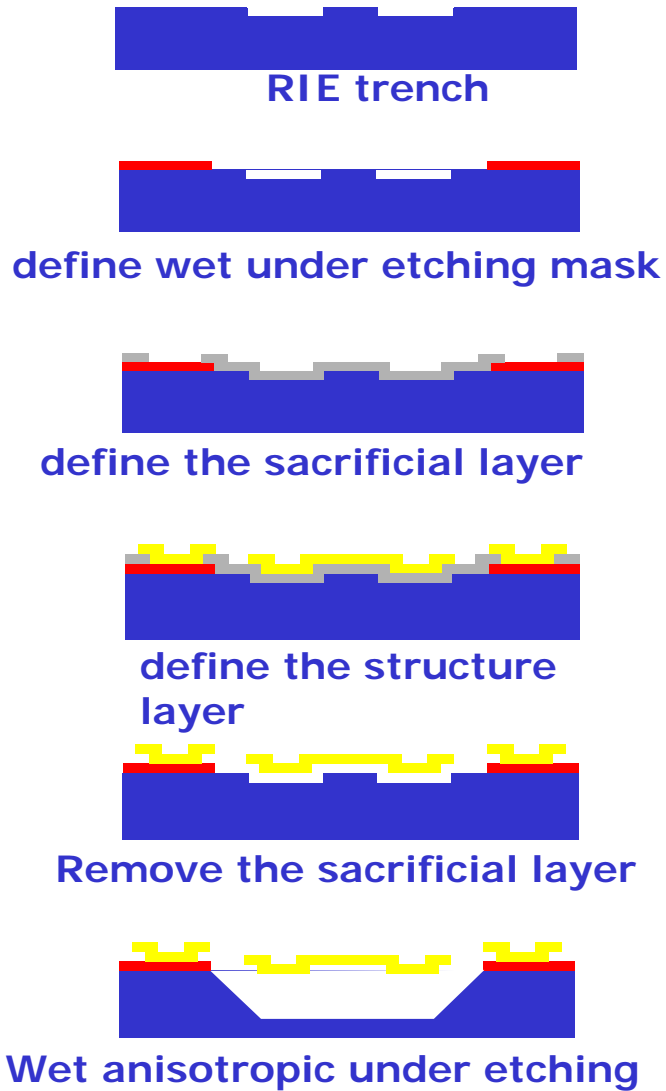


Wet anisotropic under etching



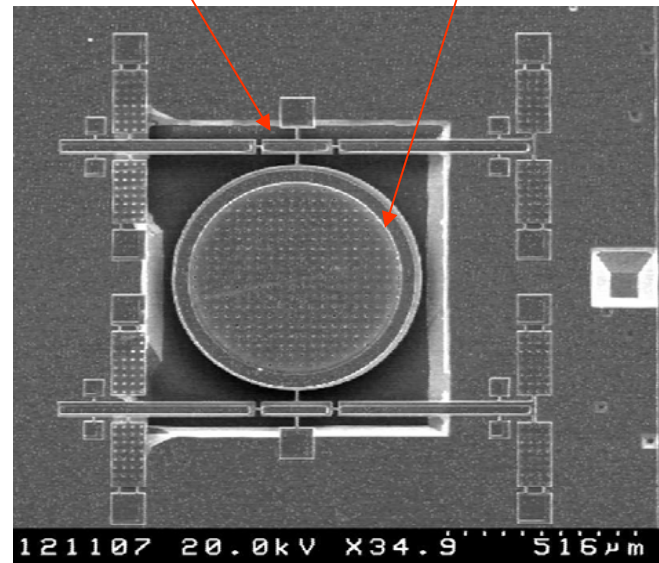
H.-Y. Lin and W. Fang, *ASME IMECE 2000*.

Micro scanner



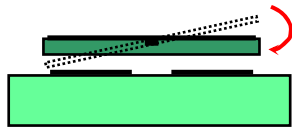
Torque generator

Folded frame

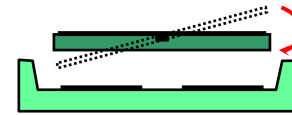


H.-Y. Lin and W. Fang, *Transducer01*, 2001

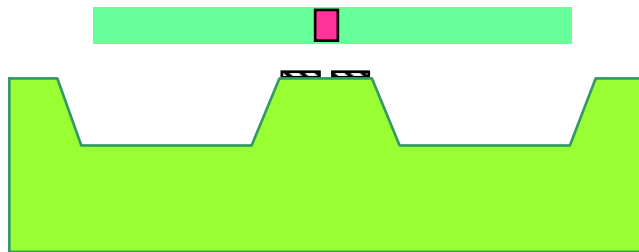
Micro scanner



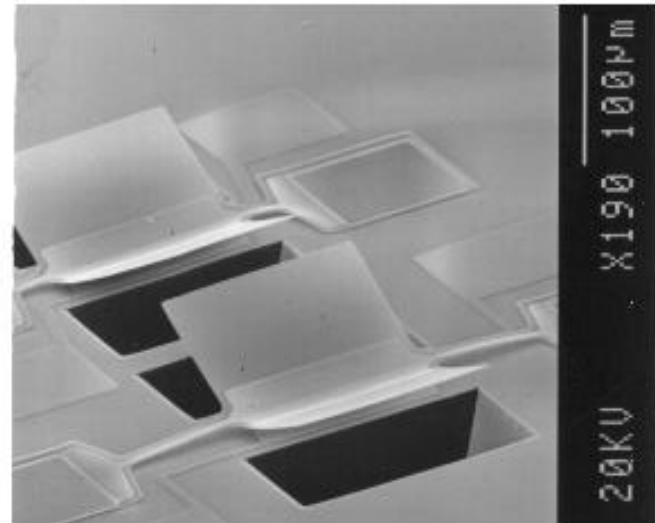
Surface device



Bulk device



Surface+ Bulk device



J. Hsieh and W. Fang, *Transducer99*, 1999

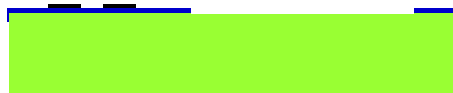
+ Fabrication processes



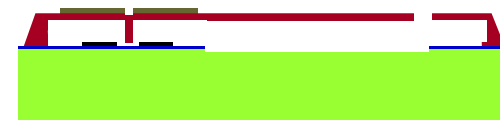
Deposit protection/isolation layer



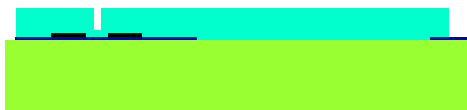
Pattern structural layer



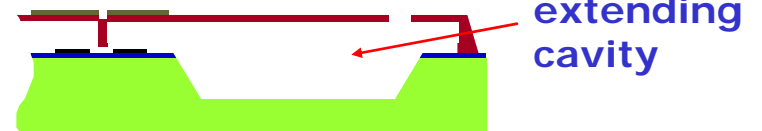
Define cavity and lower electrode



Pattern top electrode (option)
and then remove sacrificial layer

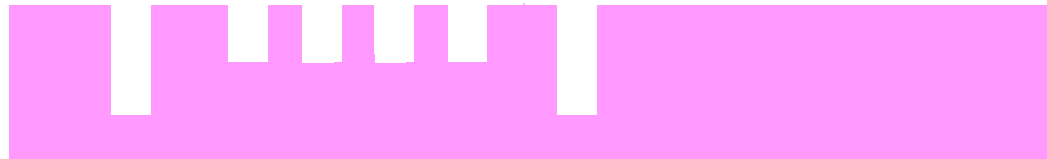


Pattern sacrificial layer

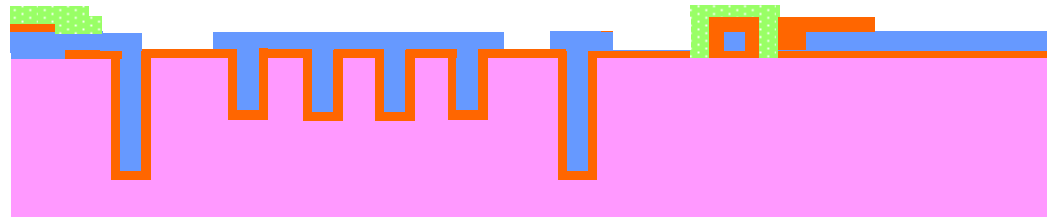


Releasing structure and etching Si

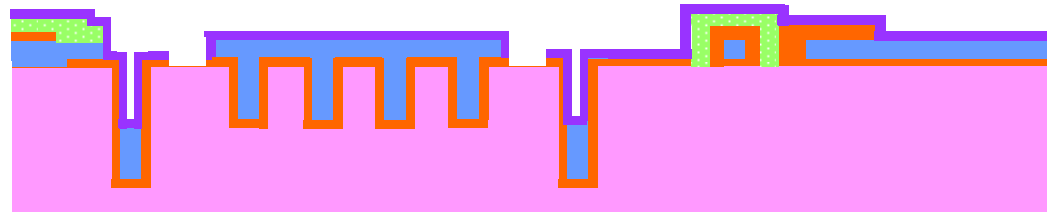
MOSBE Fabrication Platform



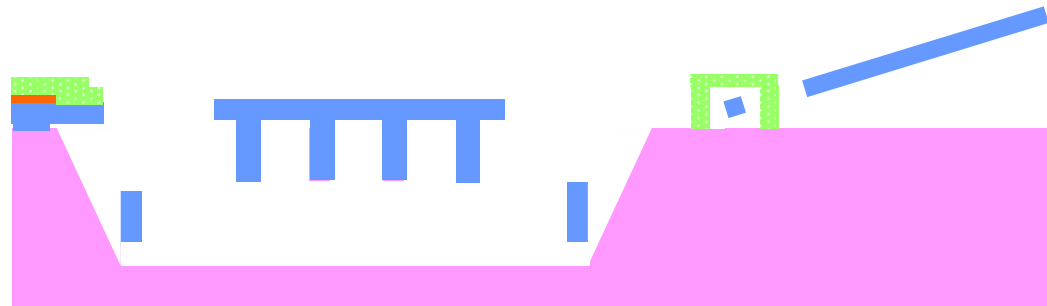
DRIE ($\sim 10 \mu\text{m}$)



MUMPs
process ($\sim 1 \mu\text{m}$)



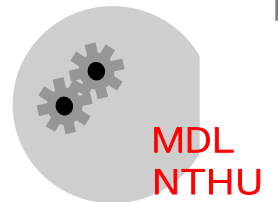
DRIE trimming
SixNy passivation



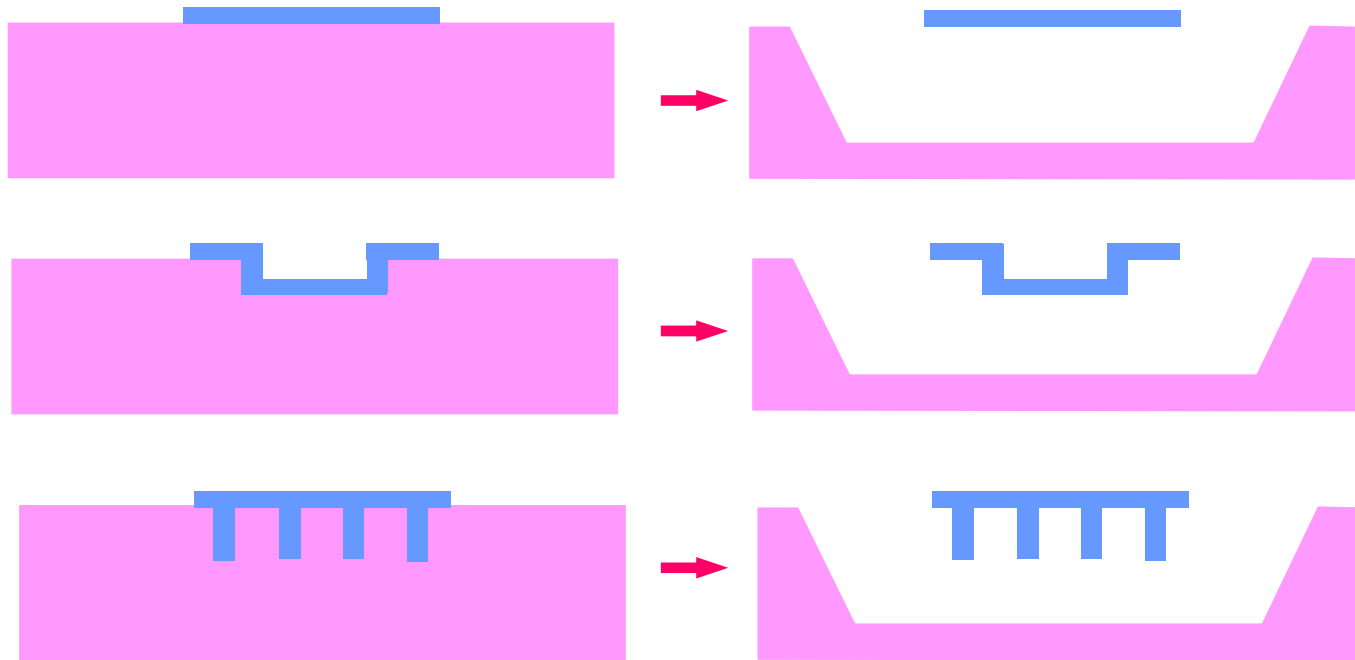
Bulk etching ($\sim 100 \mu\text{m}$)

M. Wu, C. Lai, and W. Fang, *IEEE MEMS'04*, the Netherlands, 2004

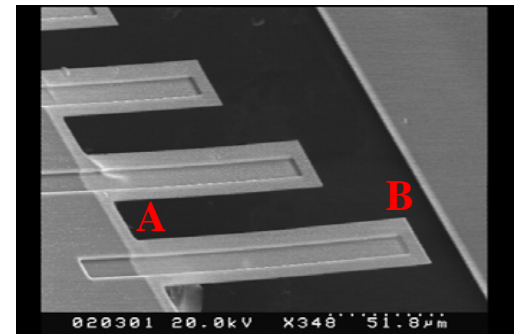
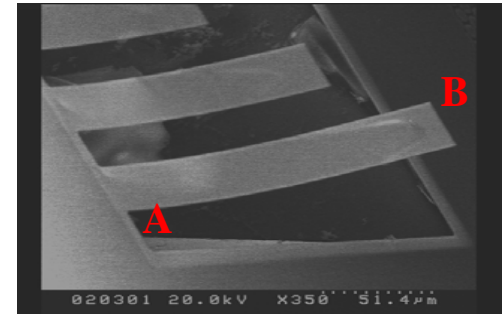
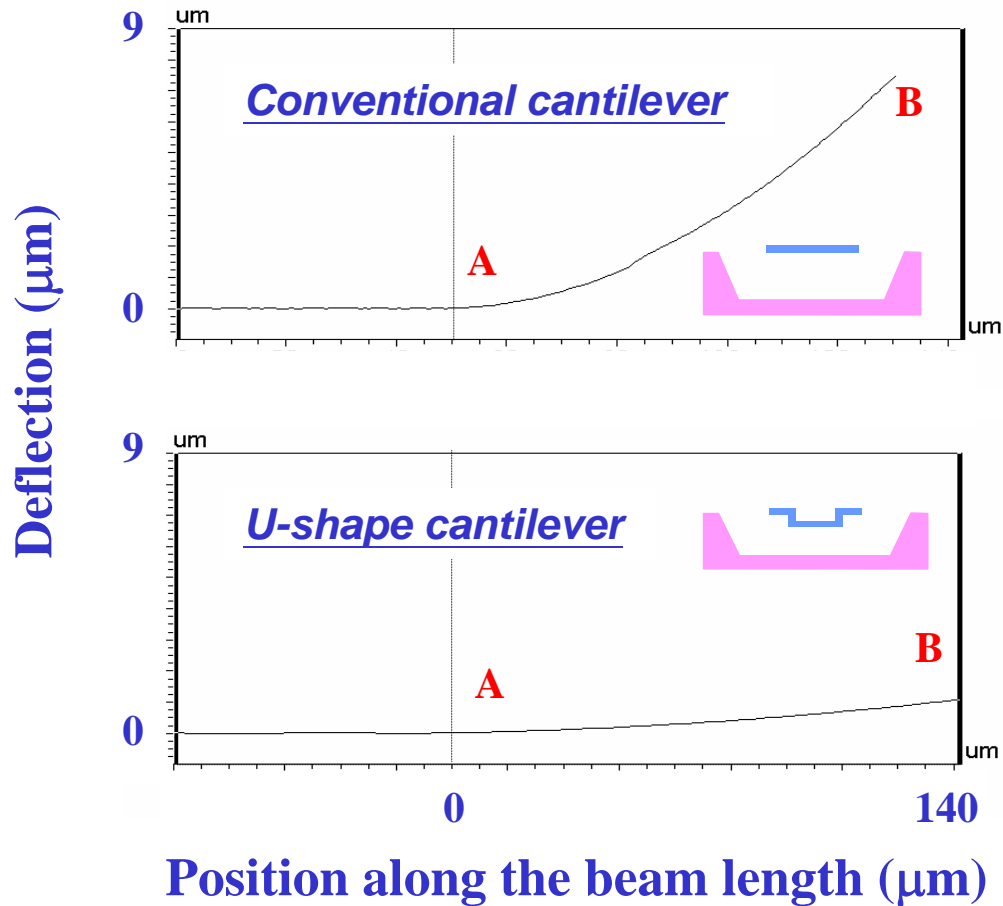
M. Wu, C. Lai, and W. Fang, *JMM*, 2005



- Increasing the stiffness of the thin poly-Si structures w/o changing the film thickness

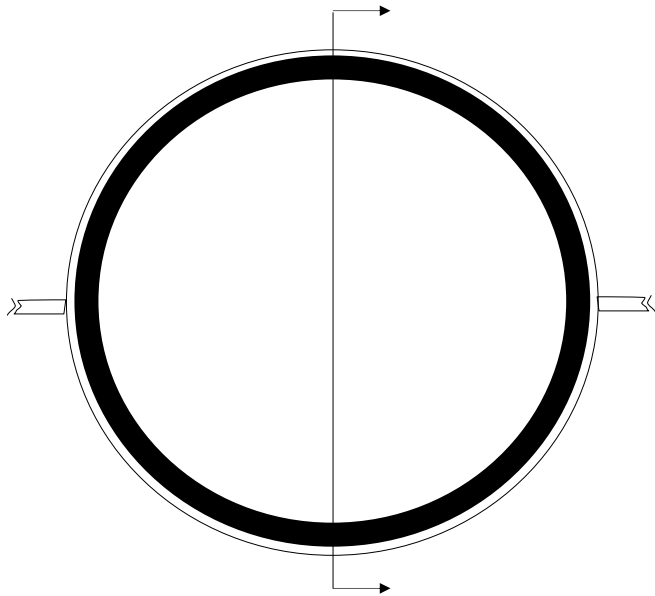


Passive component - Stiff beam

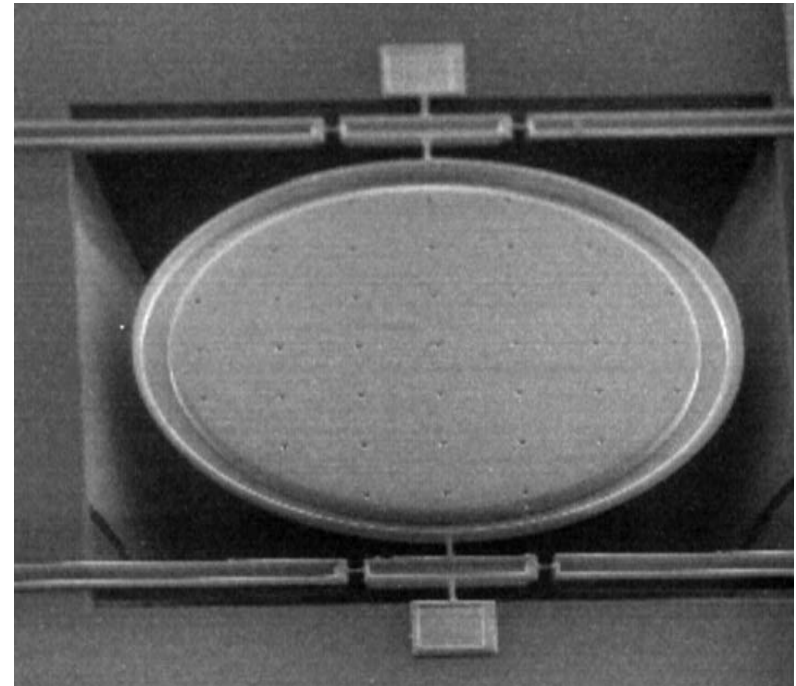


H.-Y. Lin and W. Fang, *JMM.*, 2000

Passive component - Flat mirror

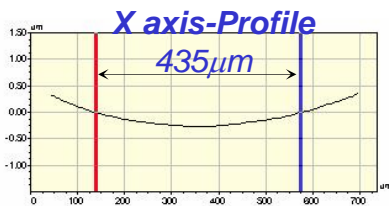
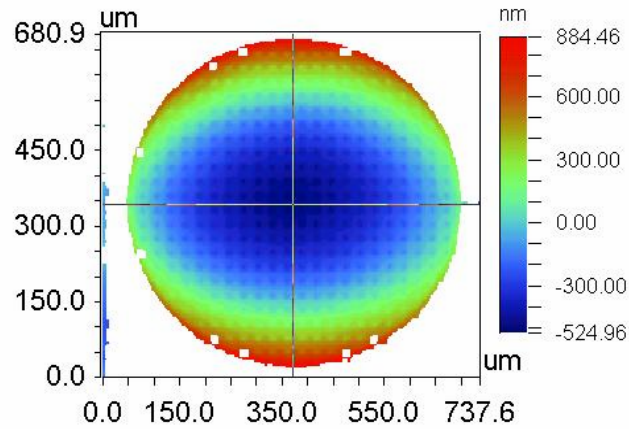


Reinforced folded frame

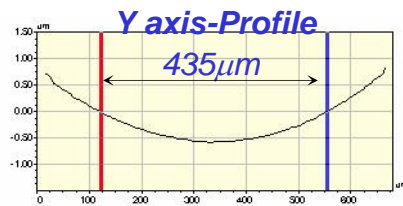


H.-Y. Lin and W. Fang, the *ASME IMECE*, Orlando, FL, 2000
H.-Y. Lin and W. Fang, *Sensors and Actuators A*, 2004

Conventional mirror

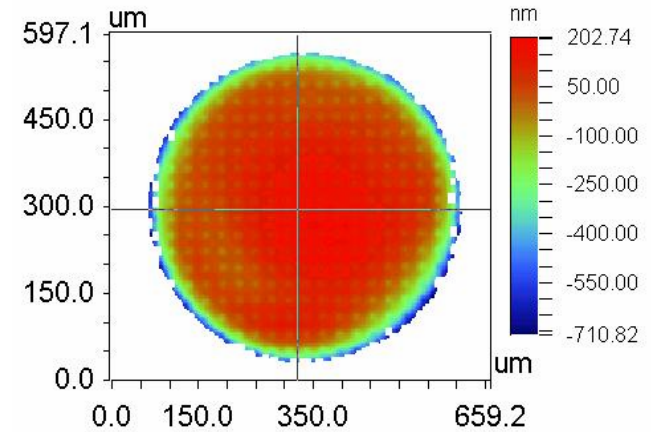


$\rho : 93\text{mm}$

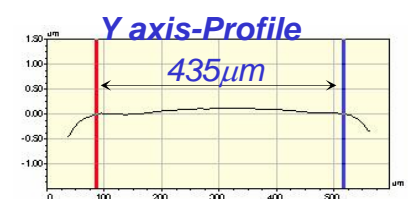


$\rho : 41\text{mm}$

MOSBE mirror



$\rho : 153\text{mm}$

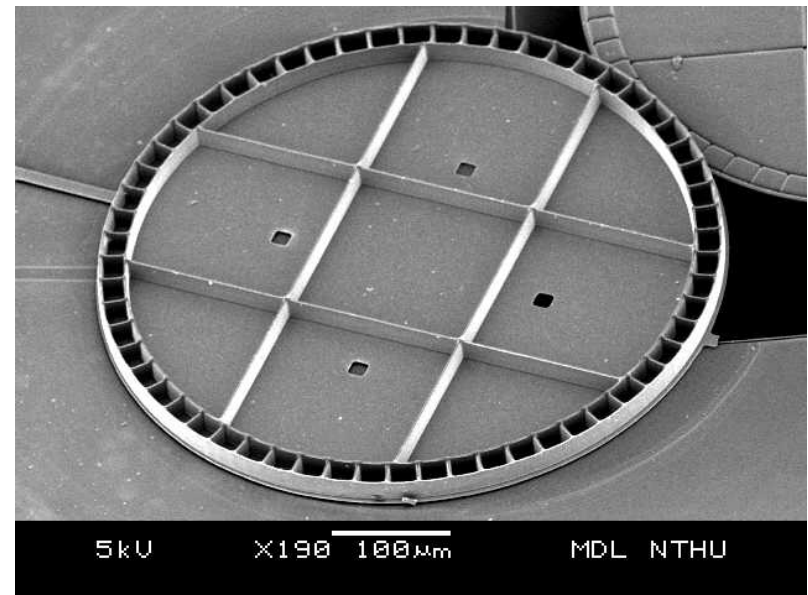
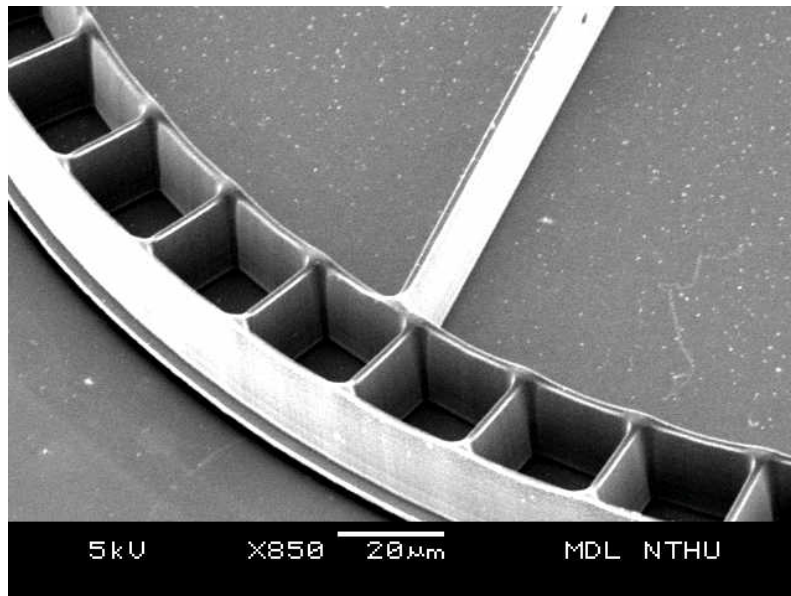


$\rho : 179\text{mm}$

H.-Y. Lin and W. Fang, the ASME IMECE, Orlando, FL, 2000

Passive component – Flat mirror

- **Narrow trench-refilled poly-Si (depth ~ 20 μm)**
 - + **Double-ring reinforced rib** on its boundary
 - + **Grid reinforced rib** on its domain

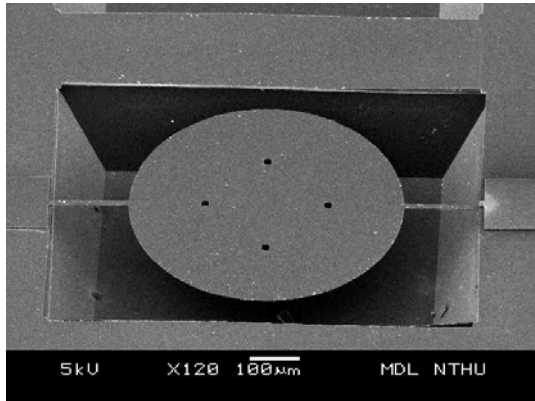


M. Wu, C. Lai, and W. Fang, *IEEE MEMS'04*, the Netherlands, 2004
M. Wu, and W. Fang, *JMM*, 2005

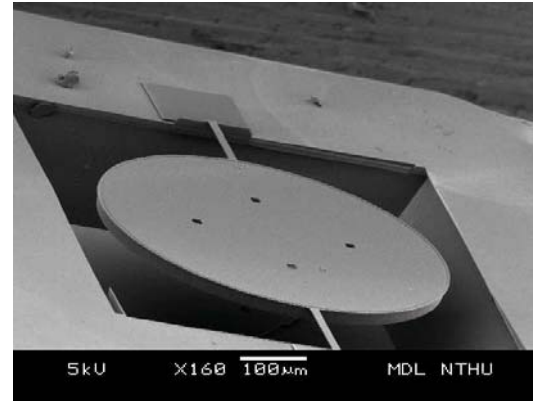
Rib-reinforced structure

- Four different type mirror

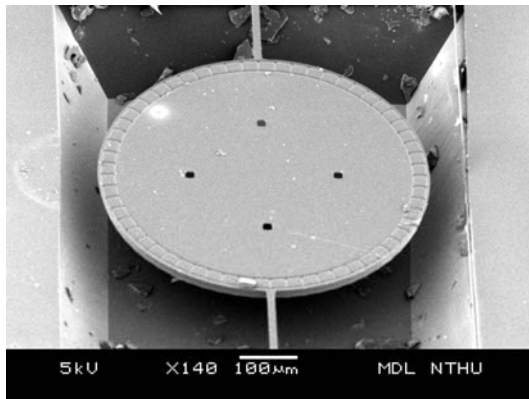
+ Thin film mirror (ROC: 19 mm)



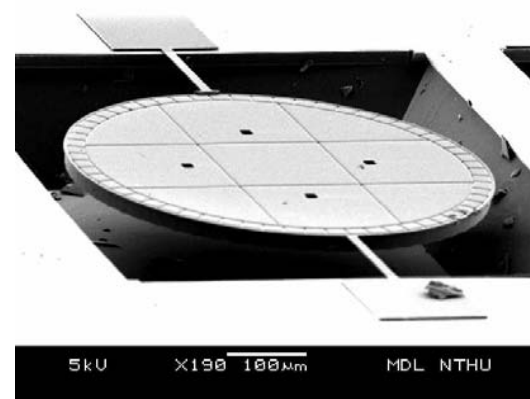
+ Single ring mirror (ROC: 64 mm)



+ Double ring mirror (ROC: 92 mm)

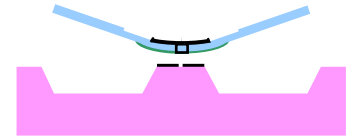


+ Double ring with grid (ROC: 150 mm)



Active component - Electrostatic actuator I

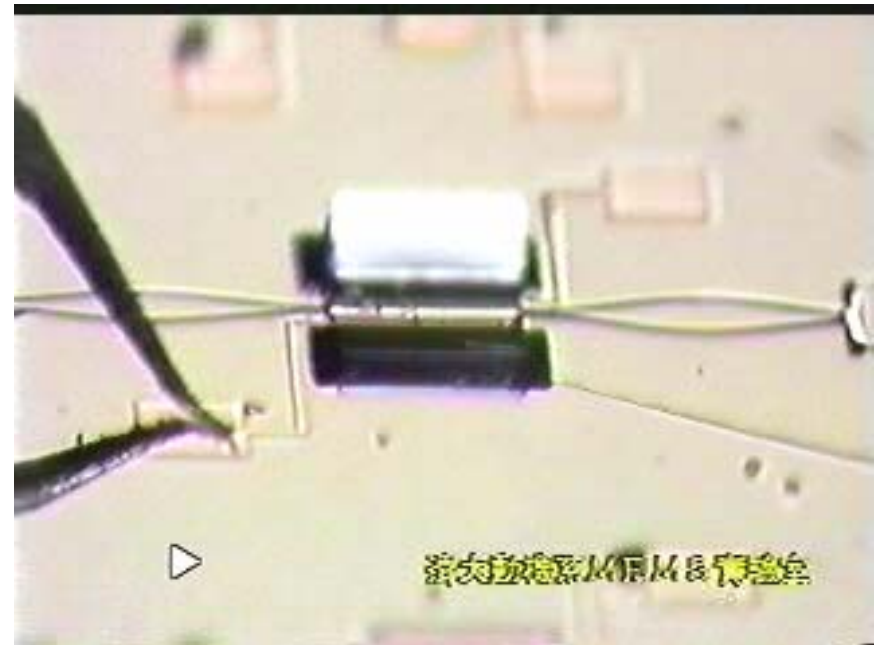
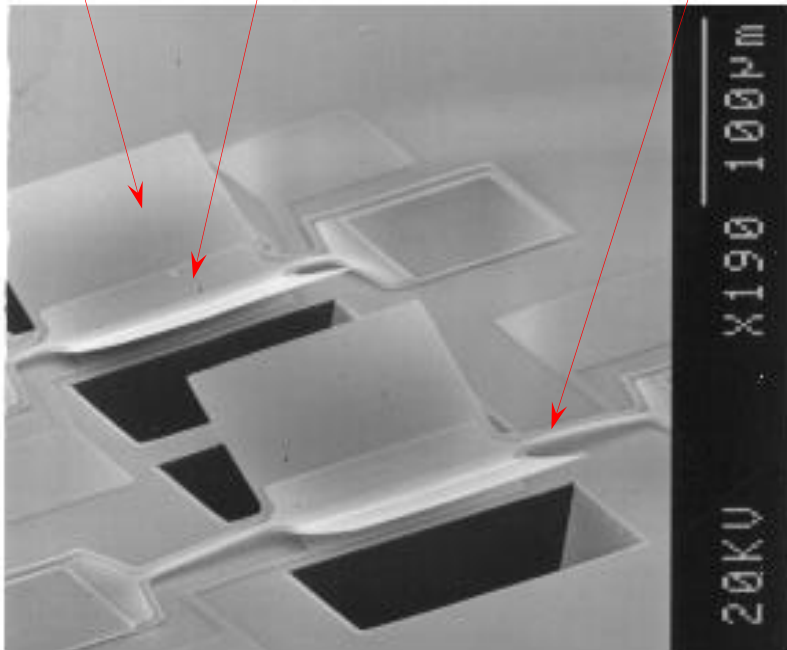
- **META Engine** : (**M**icro **E**lectrostatic **T**orsional **A**ctuator)



Plate

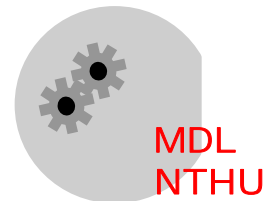
Driving electrode

Torsional spring



J. Hsieh and W. Fang, *Transducers'99*, Sendai Japan, 1999

J. Hsieh and W. Fang, *Sensors and Actuators A*, 2000

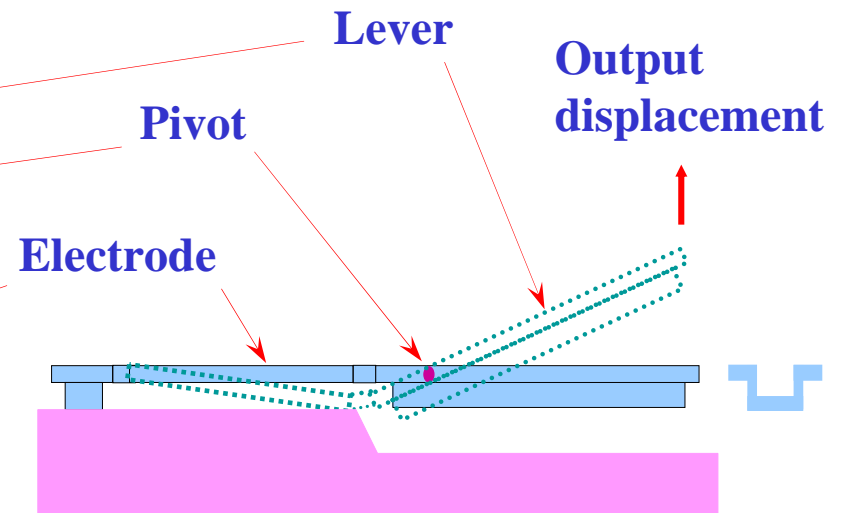
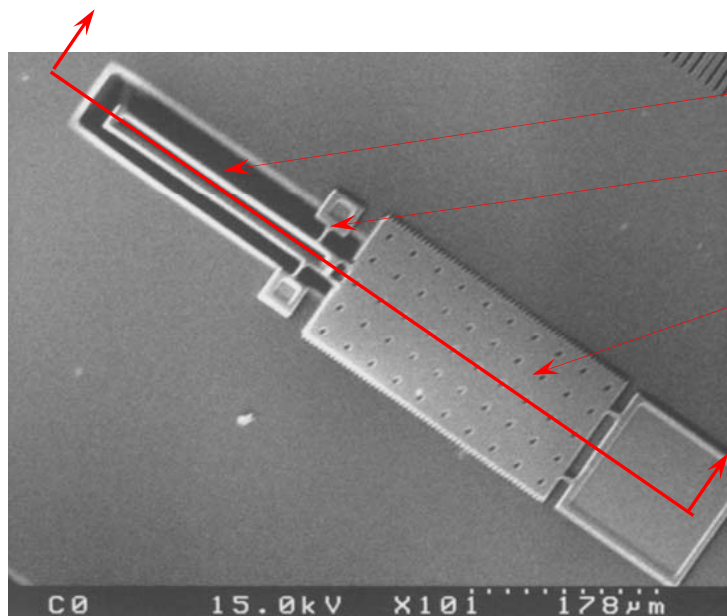


Active component - Electrostatic actuator II

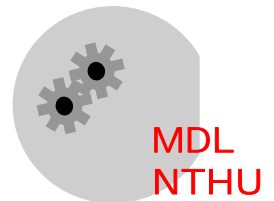
- **EDLA Engine** : (Electrostatically-Driven-Leverage Actuator)

Max disp. > 15 μ m

Driving voltage < 25 volt



H.-Y. Lin, H. Hu, and W. Fang, *Transducers'01*, Munich Germany, 2001

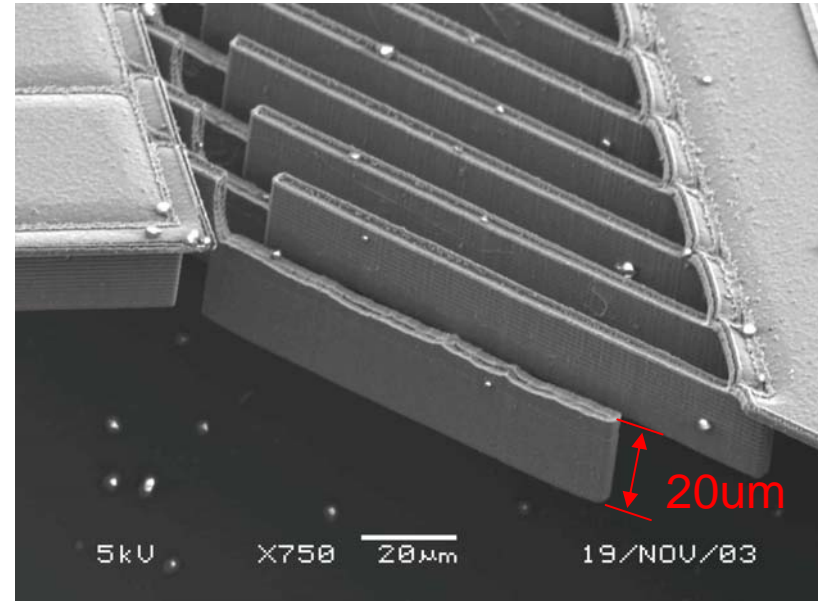
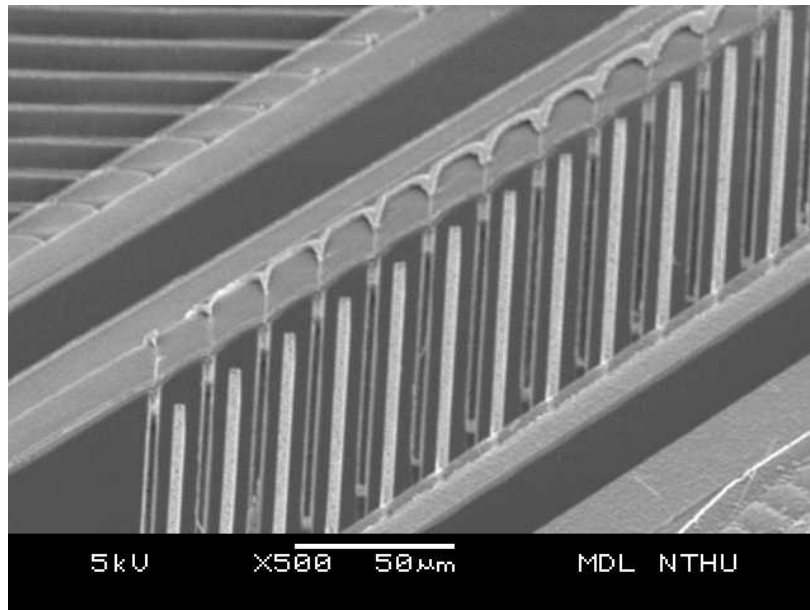
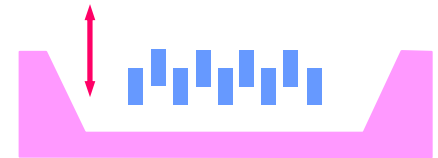


Active component - Vertical comb actuator

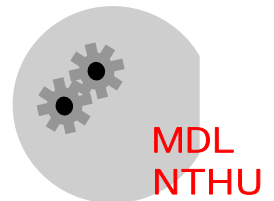
- **Vertical comb electrodes**

- + **Comb thickness ~20um**

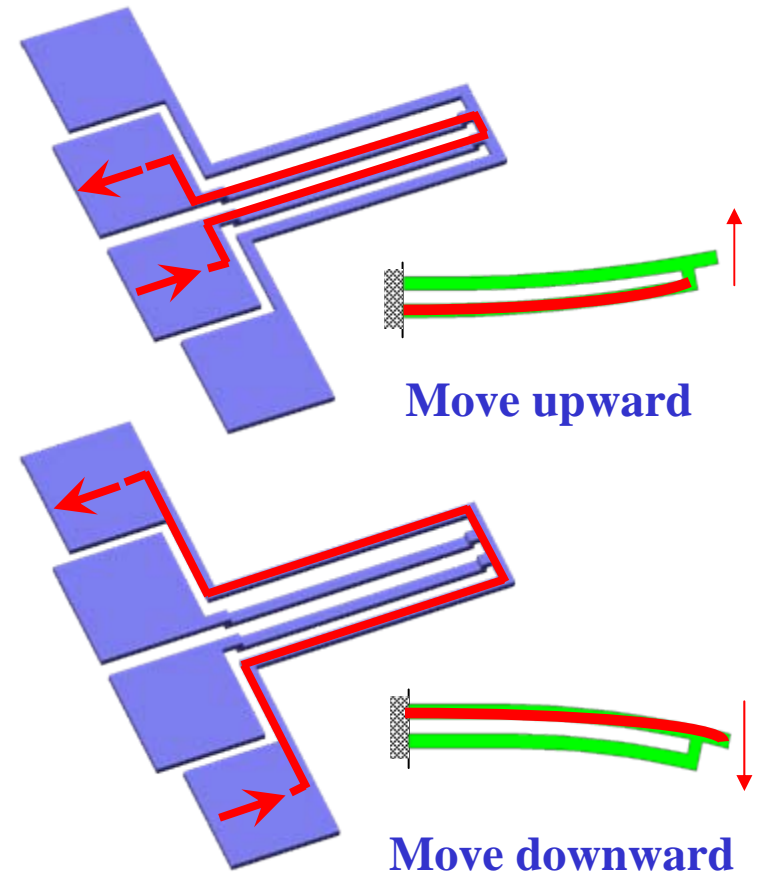
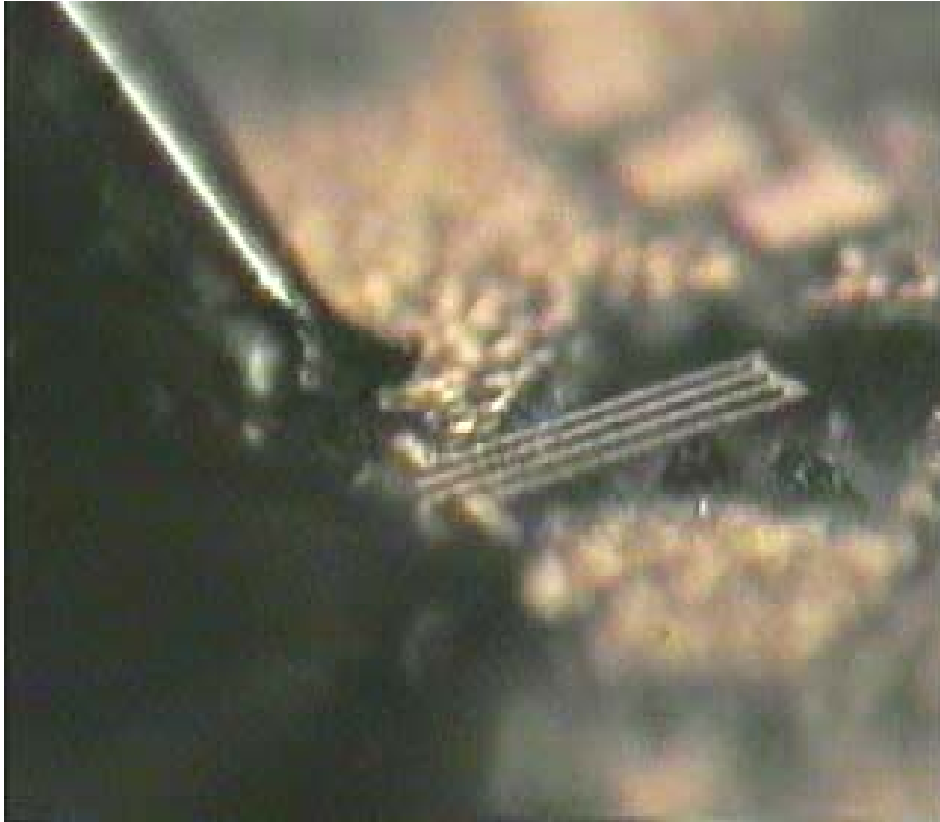
- + **Travel stroke ~20um**



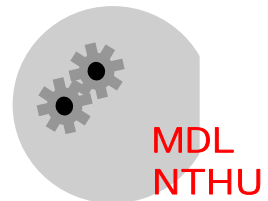
M. Wu, and W. Fang, *JMM*, 2005

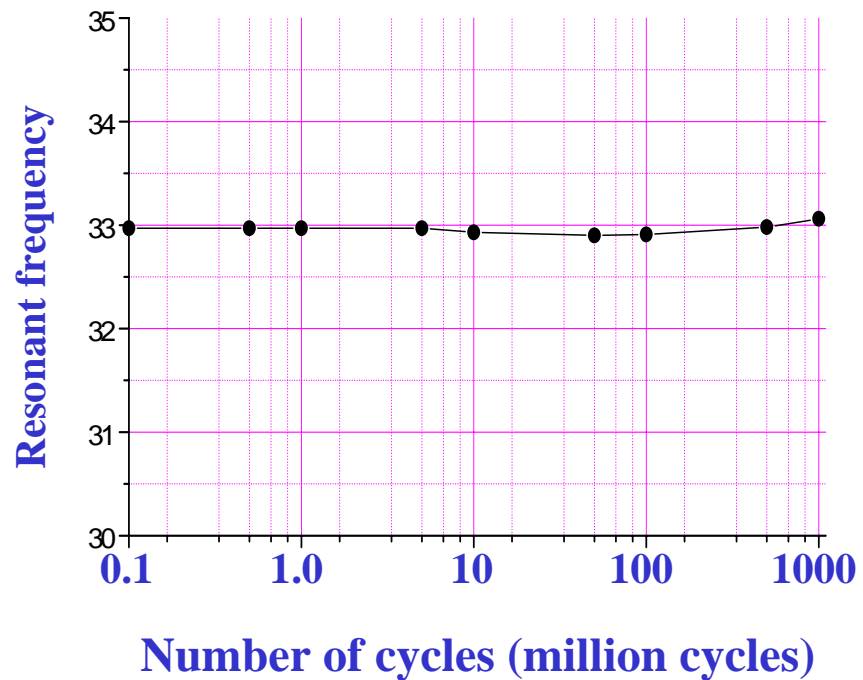
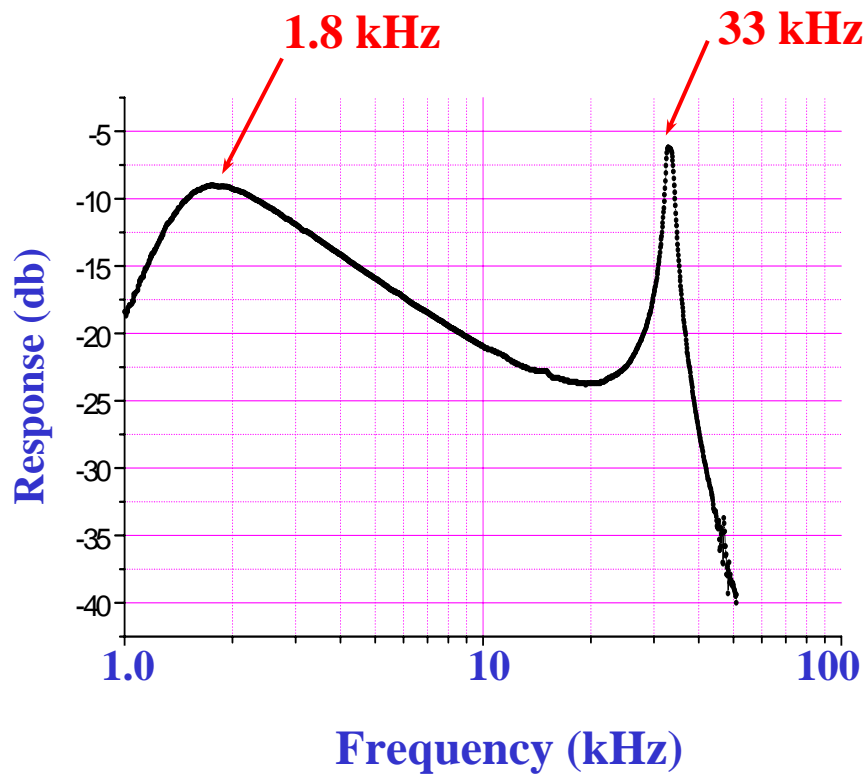


Active component - electrothermal actuator



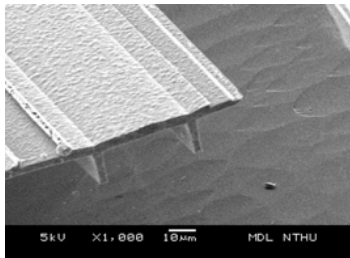
W.-C. Chen, J. Hsieh, and W. Fang, *IEEE MEMS'02*, Las Vegas, NV, 2002
W.-C. Chen, J. Hsieh, and W. Fang, *Sensors and Actuators A*, 2003



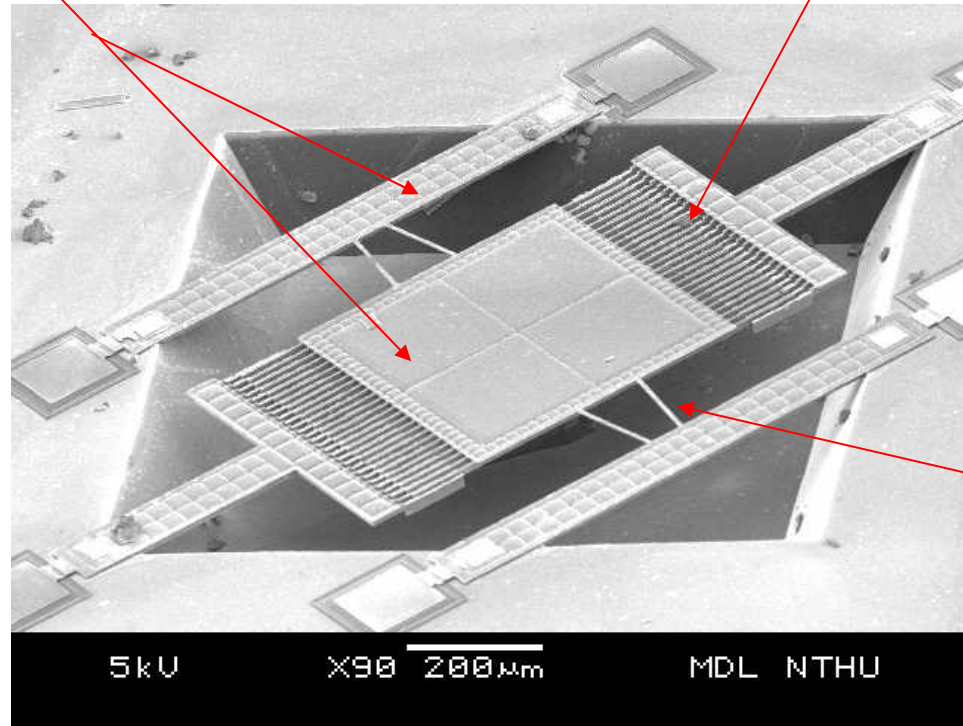
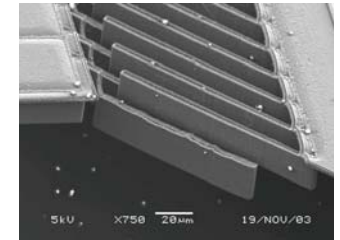
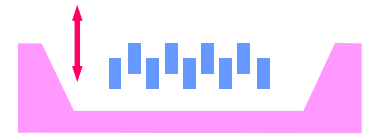


Applications – 1 axis optical scanner

Rib-reinforced mirror and frame



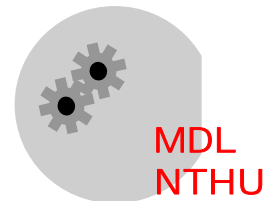
Vertical comb actuator



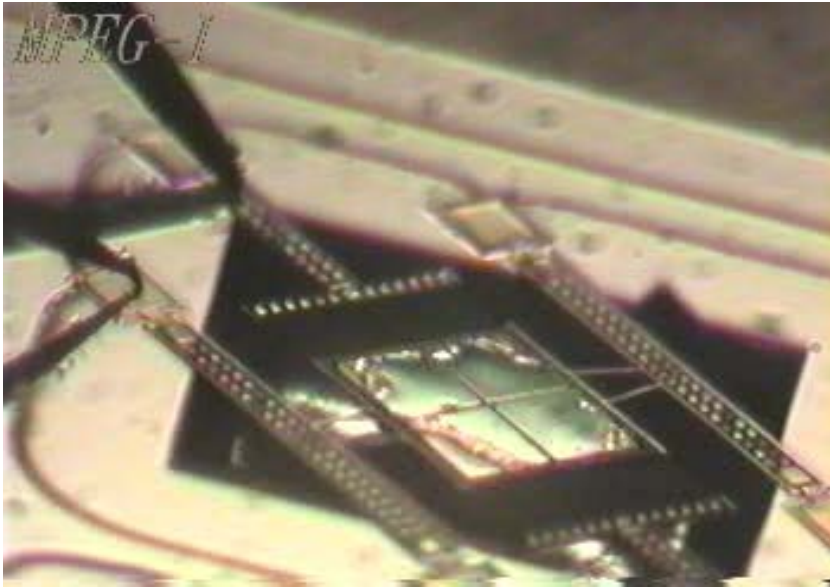
Torsional spring



M. Wu, and W. Fang, *IEEE MEMS*, Maastricht, the Netherlands, 2004
M. Wu, and W. Fang, *JMM*, 2005



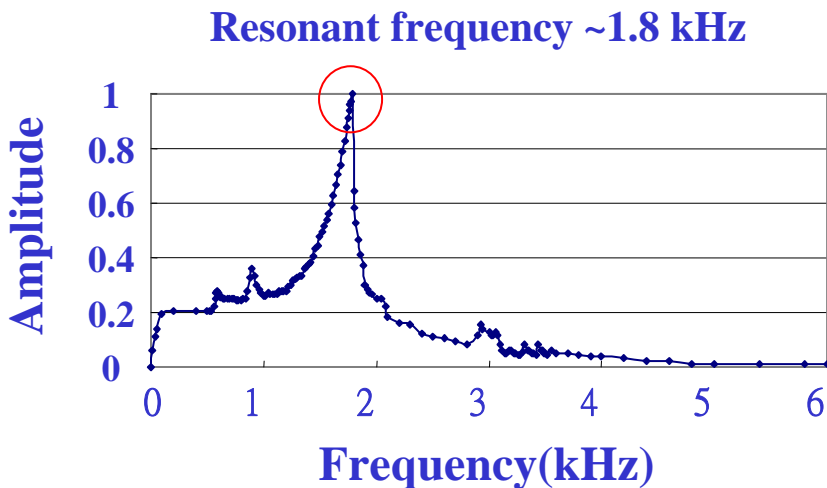
Scanning test



M. Wu, and W. Fang, *IEEE MEMS*, Masstricht, the Netherlands, 2004

Dynamic measurement

- Dynamic test driven by AC

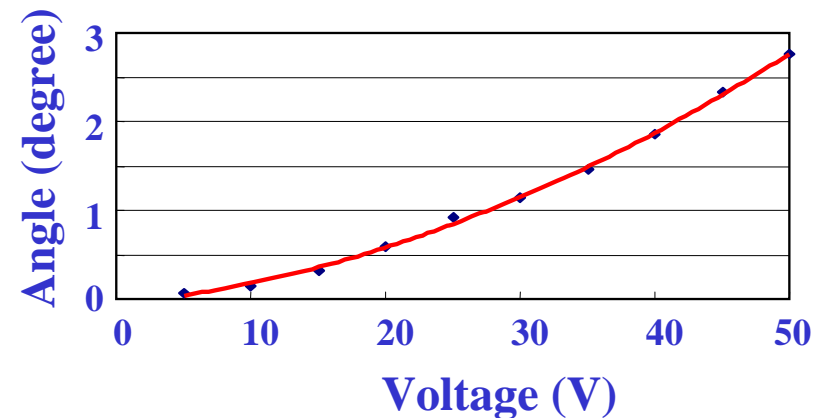


- Static load-deflection test

+ out-of plane displacement

~12.03 μ m at 50V

+ scanning angle **~ 2.8 degree**



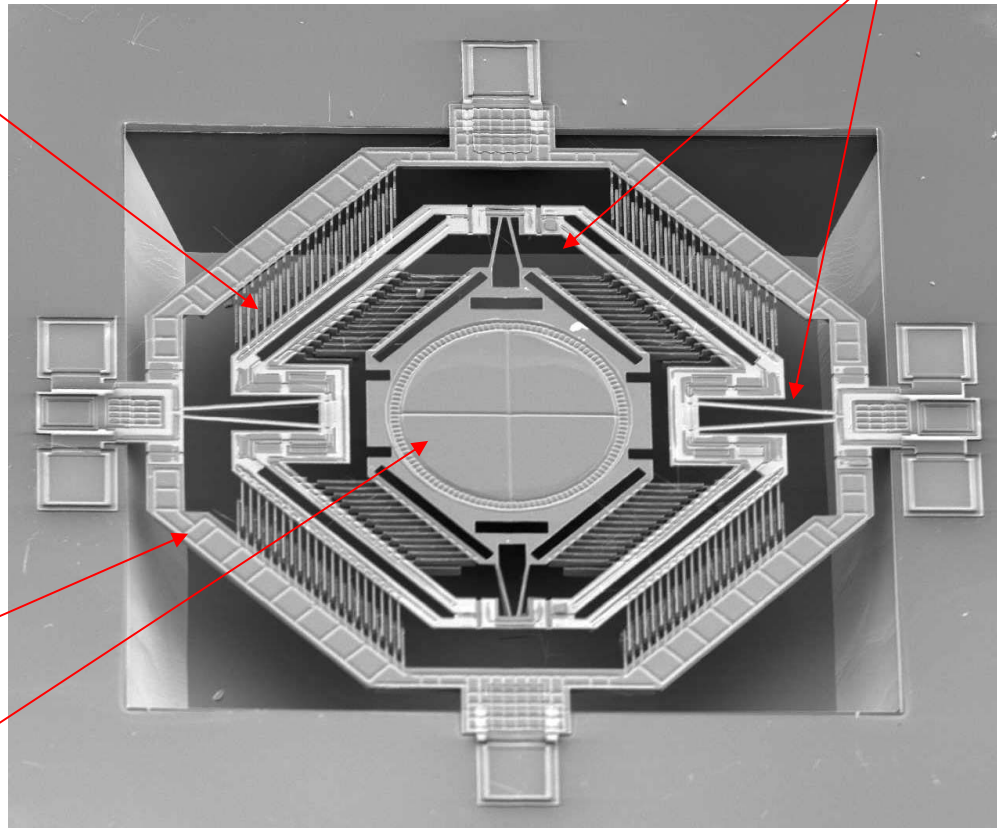
Applications - 2D Gimbal mirror

Driving electrodes
(active)



Supporting frame
(passive)

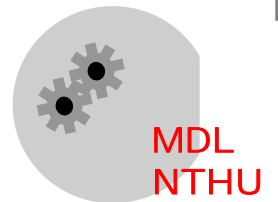
Mirror (passive)



Springs (passive)



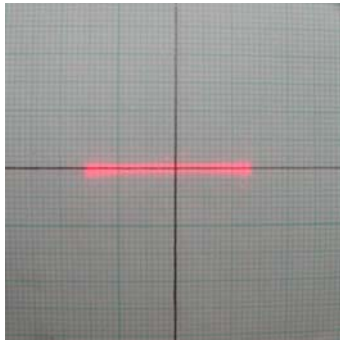
M. Wu, C. Lai, and W. Fang, *IEEE MEMS'04*, the Netherlands, 2004



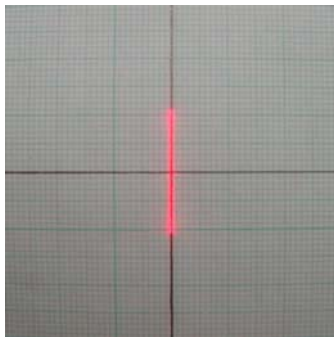
MDL
NTHU

Scanning test

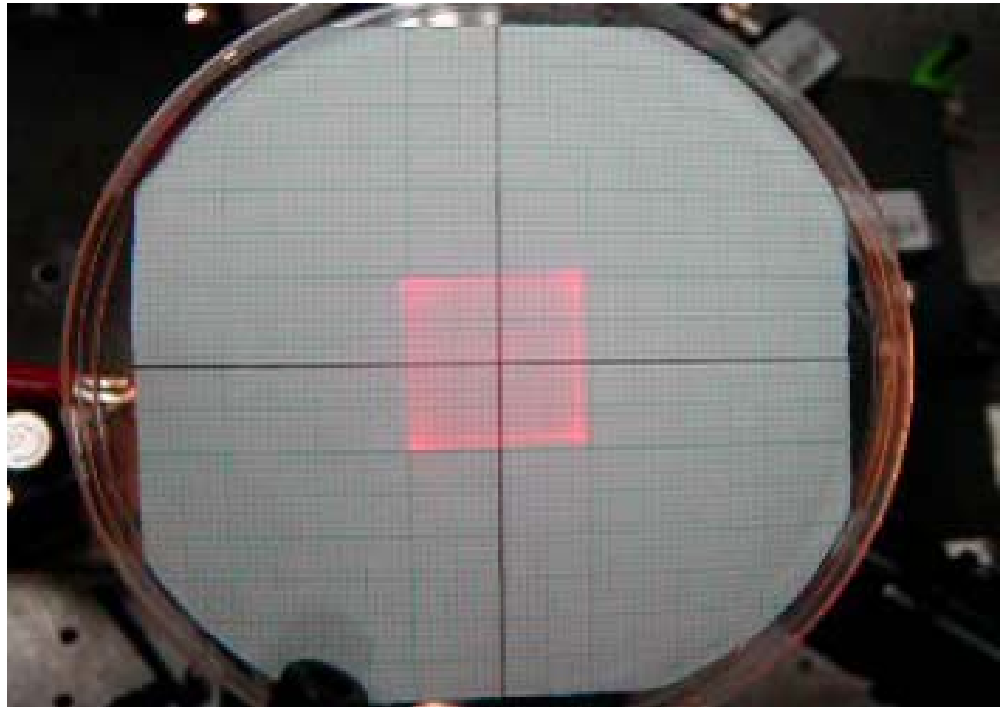
- Scanning images



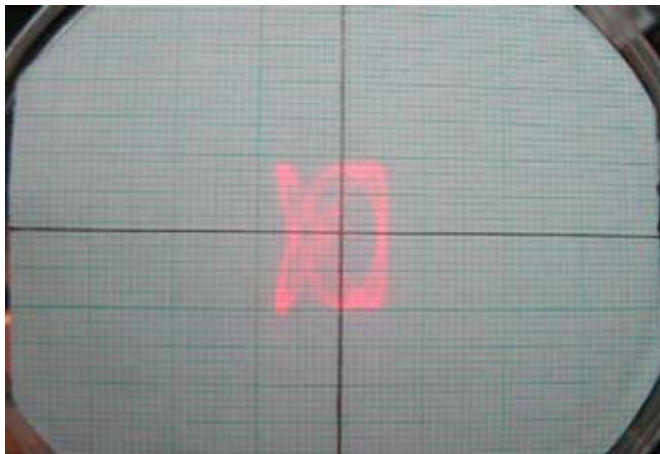
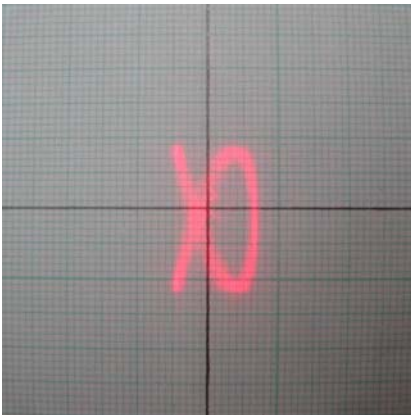
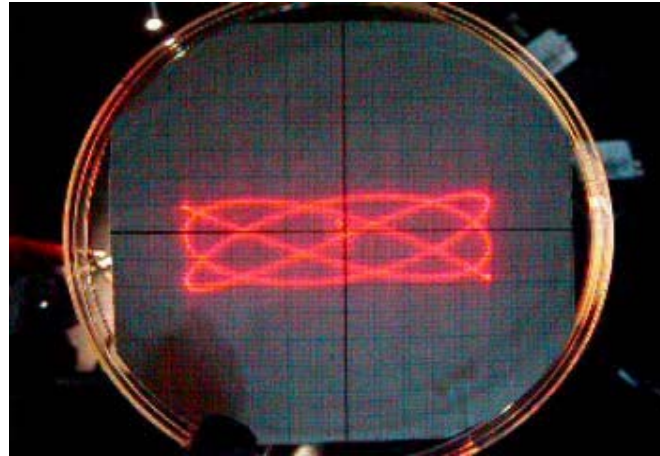
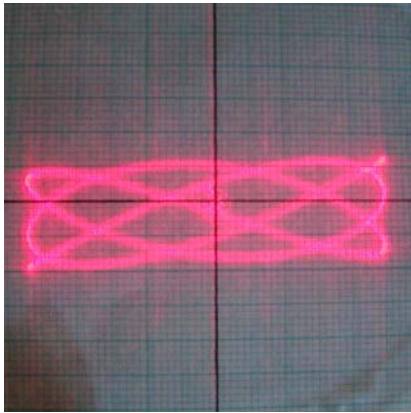
Inner axis: 4.1kHz



Outer axis: 7.1kHz

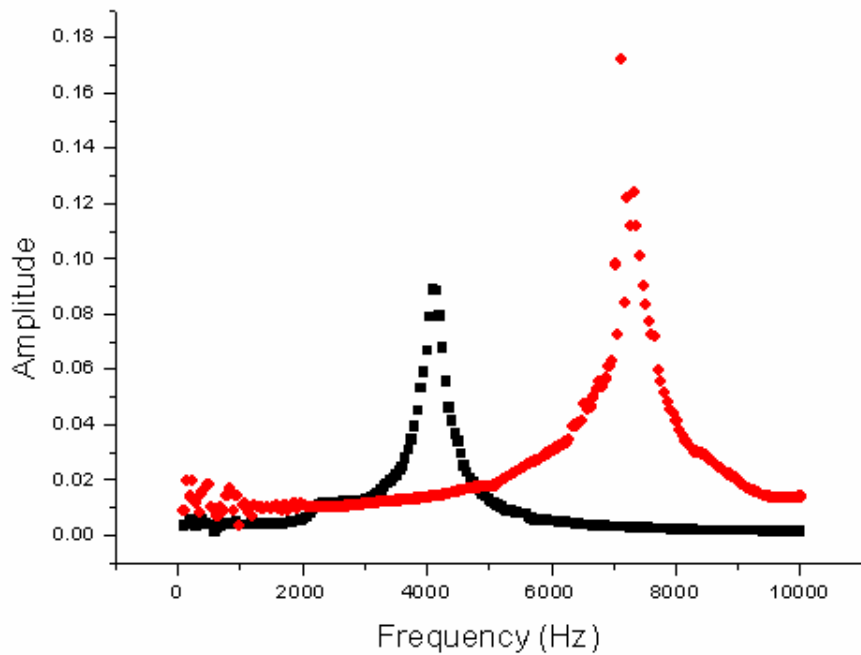


- Scanning images

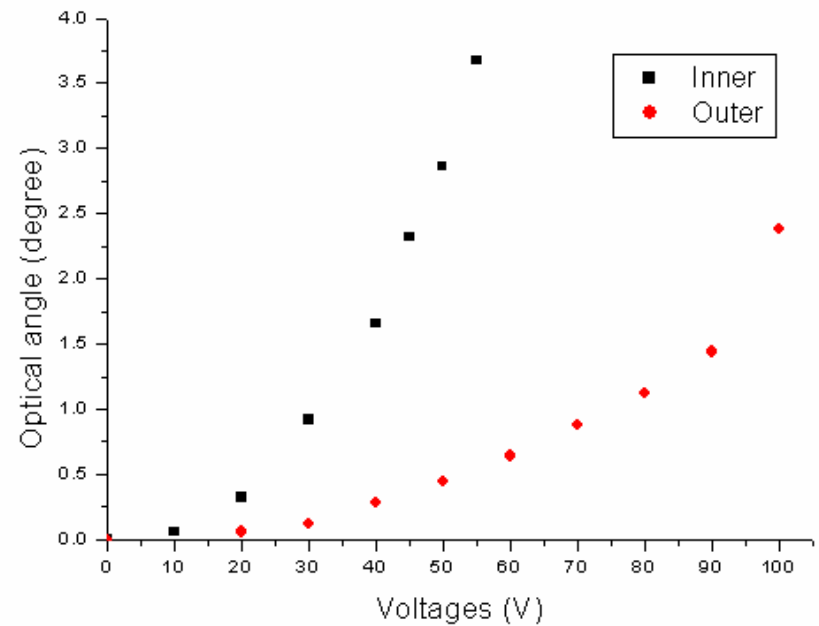


Dynamic measurement

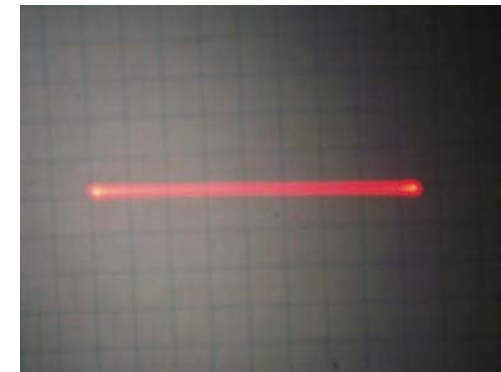
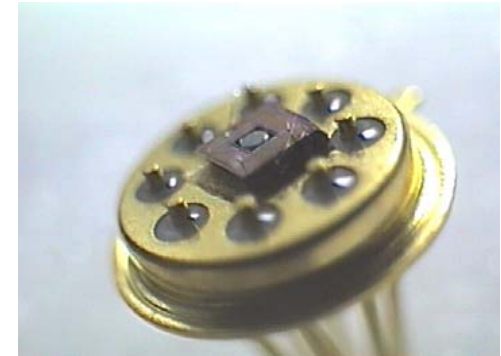
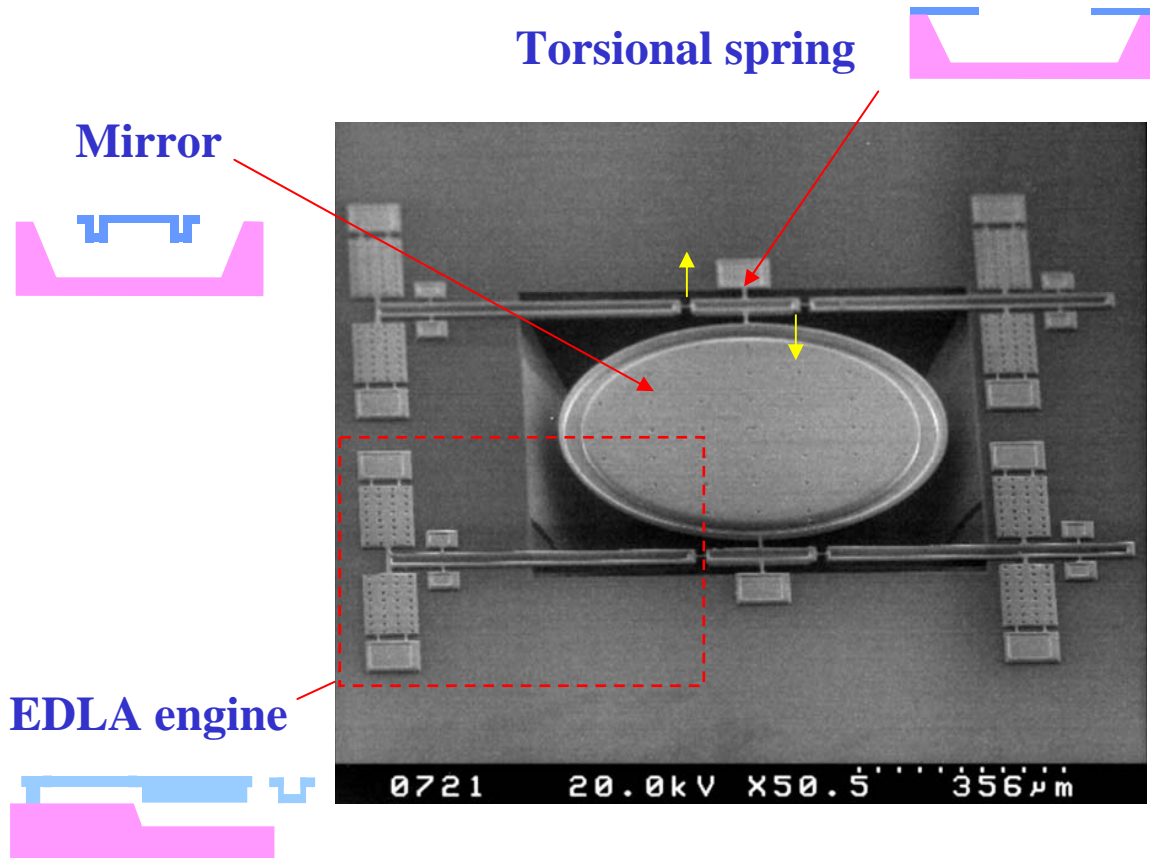
- Dynamic test driven by AC



- Static load-deflection test



Applications: optical scanner

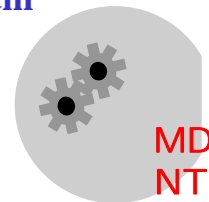


1 cm

H.-Y. Lin and W. Fang, *IEEE Optical MEMS*, Kauai, Hawaii, 2000

H.-Y. Lin and W. Fang, the *ASME IMECE*, Orlando, FL, 2000

H.-Y. Lin and W. Fang, *Sensors and Actuators A*, 2004



- Measured frequency response

